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FDN308P

SEMICONDUCTOR IM

P-Channel 2.5V Specified PowerTrench[®] MOSFET

General Description

This P-Channel 2.5V specified MOSFET uses a rugged gate version of Fairchild's advanced PowerTrench process. It has been optimized for power management applications with a wide range of gate drive voltage (2.5V - 12V).

Applications

- Power management
- Load switch
- Battery protection

Features

- -20 V, -1.5 A. $R_{DS(ON)} = 125 \text{ m}\Omega @ V_{GS} = -4.5 \text{ V}$ $R_{DS(ON)} = 190 \text{ m}\Omega @ V_{GS} = -2.5 \text{ V}$
- Fast switching speed
- High performance trench technology for extremely low $R_{\text{DS}(\text{ON})}$
- SuperSOTTM -3 provides low R_{DS(ON)} and 30% higher power handling capability than SOT23 in the same footprint





Absolute Maximum Ratings T_{A=25°C unless otherwise noted}

Symbol	Parameter			Ratings		Units
V _{DSS}	Drain-Source Voltage			-20		V
V_{GSS}	Gate-Source Voltage			±12		V
ID	Drain Curren	t – Continuous	(Note 1a)	-1.5		А
	– Pulsed			-10		
P _D	Maximum Power Dissipation		(Note 1a)	0.5		W
			(Note 1b)	0.46		
T _J , T _{STG}	Operating and Storage Junction Temperature Range			-55 to +150		°C
Therma	I Charact	eristics				
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient (Note 1a)			250		°C/W
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case (Note 1)			75		°C/W
Packag	e Marking	and Ordering	g Information			
Device Marking		Device	Reel Size	Tape width	Quantity	
308		FDN308P	7"	8mm 300		0 units

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Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Off Char	acteristics					
BV _{DSS}	Drain–Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_{D} = -250 \mu\text{A}$	-20			V
$\frac{\Delta BV_{DSS}}{\Delta T_J}$	Breakdown Voltage Temperature Coefficient	$I_D = -250 \ \mu$ A,Referenced to 25°C		-13		mV/°C
I _{DSS}	Zero Gate Voltage Drain Current	$V_{\text{DS}} = -16 \text{ V}, V_{\text{GS}} = 0 \text{ V}$			-1	μA
I _{GSSF}	Gate-Body Leakage, Forward	$V_{GS} = 12 \text{ V}, \qquad V_{DS} = 0 \text{ V}$			100	nA
I _{GSSR}	Gate-Body Leakage, Reverse	$V_{GS} = -12 \text{ V} \qquad V_{DS} = 0 \text{ V}$			-100	nA
On Char	acteristics (Note 2)					
V _{GS(th)}	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = -250 \ \mu A$	-0.6	-1.0	-1.5	V
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate Threshold Voltage Temperature Coefficient	$I_D = -250 \ \mu\text{A}, \text{Referenced to } 25^{\circ}\text{C}$		3		mV/°C
R _{DS(on)}	Static Drain–Source On–Resistance	$ \begin{array}{l} V_{GS} = -4.5 \; V, I_D = -1.5 \; A \\ V_{GS} = -2.5 \; V, I_D = -1.3 \; A \\ V_{GS} = -4.5 \; V, \; I_D = -1.5 A \; T_J \!=\! 125^\circ \! C \end{array} $		86 136 114	125 190 178	mΩ
I _{D(on)}	On–State Drain Current	$V_{\text{GS}} = -4.5 \text{ V}, \qquad V_{\text{DS}} = -5 \text{ V}$	-5			Α
g fs	Forward Transconductance	$V_{DS} = -5 V$, $I_{D} = -1.5 A$		12		S
Dynamic	Characteristics					
C _{iss}	Input Capacitance	$V_{DS} = -10 V$, $V_{GS} = 0 V$,		341		pF
Coss	Output Capacitance	f = 1.0 MHz		83		pF
Crss	Reverse Transfer Capacitance			43		pF
t _{d(on)}	Turn–On Delay Time	$V_{DD} = -10 V$, $I_D = -1 A$,		8	16	ns
t _r	Turn–On Rise Time	$V_{GS} = -4.5 \text{ V}, \qquad R_{GEN} = 6 \Omega$		10	20	ns
t _{d(off)}	Turn-Off Delay Time			12	22	ns
t _f	Turn–Off Fall Time			8	16	ns
Qg	Total Gate Charge	$V_{DS} = -10V$, $I_D = -1.5 A$,		3.8	5.4	nC
Q _{gs}	Gate-Source Charge	$V_{GS} = -4.5 V$		0.8		nC
Q _{gd}	Gate-Drain Charge			1.0		nC
Drain-S	ource Diode Characteristics	and Maximum Ratings				
Is	Maximum Continuous Drain–Source Diode Forward Current				-0.42	Α
V _{SD}	Drain–Source Diode Forward	$V_{GS} = 0 \ V, I_S = -0.42 (Note 2)$		-0.7	-1.2	V

Notes:

1. R_{0JA} is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins. $R_{\theta JC}$ is guaranteed by design while $R_{\theta CA}$ is determined by the user's board design.

a) 250°C/W when mounted on a 0.02 in² pad of 2 oz. copper.

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b) 270°C/W when mounted on a minimum pad.

6 Scale 1 : 1 on letter size paper

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2. Pulse Test: Pulse Width \leq 300 μ s, Duty Cycle \leq 2.0%



FDN308P Rev B(W)



FDN308P Rev B(W)

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